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				APPLICANT	10.000,001				
LIST OF	REFE	RENCES CITED BY A	PPLICANT	Hirohiko WATANABE, et al.					
				FILING DATE		GROUP			
				February 1, 2006		3744			
U.S. PATENT DOCUMENTS									
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE			
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
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